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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
09/942,784	08/31/2001	Tae-Woong Kang	0630-1187P	9755
2292	7590 06/23/2003			
BIRCH STEWART KOLASCH & BIRCH			EXAMINER	
PO BOX 747 FALLS CHURCH, VA 22040-0747			CHEN, KIN CHAN	
			ART UNIT	PAPER NUMBER
			1765	7
			DATE MAILED: 06/23/2003	/

Please find below and/or attached an Office communication concerning this application or proceeding.

		Application No.	Applicant(s)				
Office Action Summary		09/942,784	KANG, TAE-WOONG				
		Examin r	Art Unit				
	,	Kin-Chan Chen	1765				
	The MAILING DATE of this communication app			-			
Period for Reply							
THE - Exte after - If the - If NO - Failu - Any	ORTENED STATUTORY PERIOD FOR REPLY MAILING DATE OF THIS COMMUNICATION. nsions of time may be available under the provisions of 37 CFR 1.13 SIX (6) MONTHS from the mailing date of this communication. e period for reply specified above is less than thirty (30) days, a reply o period for reply is specified above, the maximum statutory period we tree to reply within the set or extended period for reply will, by statute, reply received by the Office later than three months after the mailing ed patent term adjustment. See 37 CFR 1.704(b).	36(a). In no event, however within the statutory mining will apply and will expire S cause the application to	wer, may a reply be timely filed mum of thirty (30) days will be considered timely. EIX (6) MONTHS from the mailing date of this communication. become ABANDONED (35 U.S.C. § 133).				
1)⊠	Responsive to communication(s) filed on 27 h	<i>1ay 2003</i> .					
2a)⊠	This action is FINAL . 2b) ☐ Thi	is action is non-fir	nal.				
3) Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213.							
· · ·	ion of Claims						
-	Claim(s) <u>1-20</u> is/are pending in the application						
	4a) Of the above claim(s) is/are withdrawn from consideration.						
· _	Claim(s) <u>20</u> is/are allowed.						
_							
7)⊠							
8)(8	Claim(s) are subject to restriction and/or ion Papers	r election requiren	nent.				
_	The specification is objected to by the Examiner	r					
·	The drawing(s) filed on is/are: a) accep		ed to by the Examiner				
.0/	Applicant may not request that any objection to the						
11) ☐ The proposed drawing correction filed on is: a) ☐ approved b) ☐ disapproved by the Examiner.							
If approved, corrected drawings are required in reply to this Office action.							
12) The oath or declaration is objected to by the Examiner.							
Pri rity under 35 U.S.C. §§ 119 and 120							
13) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).							
a)	☐ All b)☐ Some * c)☐ None of:						
	1. Certified copies of the priority documents	s have been recei	ved.				
	2. Certified copies of the priority documents have been received in Application No						
* (3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).						
* See the attached detailed Office action for a list of the certified copies not received.							
14) Acknowledgment is made of a claim for domestic priority under 35 U.S.C. § 119(e) (to a provisional application).							
 a) ☐ The translation of the foreign language provisional application has been received. 15)☐ Acknowledgment is made of a claim for domestic priority under 35 U.S.C. §§ 120 and/or 121. 							
Attachmen							
2) Notic	ce of References Cited (PTO-892) ce of Draftsperson's Patent Drawing Review (PTO-948) mation Disclosure Statement(s) (PTO-1449) Paper No(s)	5) 🔲	Interview Summary (PTO-413) Paper No(s) Notice of Informal Patent Application (PTO-152) Other:				

U.S. Patent and Trademark Office PTO-326 (Rev. 04-01)

DETAILED ACTION

Drawings

1. Figures 1A-1G should be designated by a legend such as --Prior Art-- because only that which is old is illustrated. See MPEP § 608.02(g). A proposed drawing correction or corrected drawings are required in reply to the Office action to avoid abandonment of the application. The objection to the drawings will not be held in abeyance. Fig. 1A-1G is a conventional art, see page 2, lines 11-12 as evidence.

Claim Rejections - 35 USC § 102

2. Claims 1, 5, 11, and 12 are rejected under 35 U.S.C. 102(e) as being anticipated by admitted prior art.

In a method for forming a capacitor of a semiconductor device, admitted prior art (conventional art) teaches that a first, second, and a third insulation layer may be formed sequentially on a semiconductor substrate (Fig. 1A). The third and the second insulation layer may be sequentially etched to form at least one hole over a first region of the semiconductor substrate (Fig. 1B). A conductive layer may be formed over the semiconductor substrate (Fig. 1C). CMP may be performed until an upper surface of the third insulation layer is exposed (Fig. 1E, page 2 of the specification, lines 8-10). Portions of the third insulation layer may be removed from the first region (Fig. 1F and

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1G). As to dependent claim 5, admitted prior art teaches said material (pages 2 of the specification, line 16).

Claim Rejections - 35 USC § 103

- 3. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 4. Claims 2-4, 17, and 19 are rejected under 35 U.S.C. 102(e) as anticipated by or, in the alternative, under 35 U.S.C. 103(a) as obvious over admitted prior art.

In a method for forming a capacitor of a semiconductor device, admitted prior art (conventional art) teaches that a first, second, and a third insulation layer may be formed sequentially on a semiconductor substrate (Fig. 1A). The third and the second insulation layer may be sequentially etched to form at least one hole over a first region of the semiconductor substrate (Fig. 1B). A conductive layer may be formed over the semiconductor substrate (Fig. 1C). CMP may be performed until an upper surface of the third insulation layer is exposed (Fig. 1E, page 2 of the specification, lines 8-10). Portions of the third insulation layer may be removed from the first region (Fig. 1F and 1G).

Admitted prior art teaches the second insulation material may be silicon nitride and the third insulation material may be silicon oxide (pages 2 of the specification, line

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20-23). Because same materials are used in the same process, it would inherently contain same etching properties (having different characteristic with respect to each other in instant claim 2) and same functions (produce non-sharp upper edges of the conductive layer in claims 17 and 19).

Claim 18 is rejected under 35 U.S.C. 103(a) as being unpatentable over admitted prior art.

Admitted prior art does not explicitly state that the slurry material may be removed from the first region. However, it would have been obvious to one with ordinary skill in the art to clean (remove) the slurry in the device because it is conventional to keep the semiconductor device as clean as possible and remove unneeded material for the product during semiconductor device fabrication.

5. Claims 13-15 are rejected under 35 U.S.C. 103(a) as being unpatentable over admitted prior art in view of Matsuoka et al. (US 5,130,449; hereinafter " Matsuoka ").

The discussion of modified Matsuoka from above is repeated here.

Claim 13 differs from admitted prior art by specifying using wet etching for removing the insulation material over a conductive material. However, it is conventional to use wet etching method for removing the insulation material over a conductive material. Matsuoka is only relied on the show this conventional method (col. 12, lines 10-13). Because it is conventional and because it is disclosed by Matsuoka, hence, it would have been obvious to one with ordinary skill in the art to modify the method of admitted prior art by using wet etching method for removing the insulation material over

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a conductive material in order to provide their art recognized advantages and produce

an expected result.

As to dependent claims 14 and 15, Matsuoka is not particular about the wet

station being used in the wet etching process. Hence, it would have been obvious to

one with ordinary skill in the art to use wet station employing an IPA vapor drier

because it is one of the most popular wet station for wet etching process.

Response to Arguments

6. Applicant's arguments filed May 27, 2003 have been fully considered but they are

not persuasive.

Applicant has argued that there is no admission as to prior art. In response, in

specification, page 2, lines 11-12, applicant clearly states that the processes steps of

Fig. 1A-1G is conventional.

Allowable Subject Matter

7. Claim 20 is allowed.

Claims 6-10 and 16 are objected to as being dependent upon a rejected base

claim, but would be allowable if rewritten in independent form including all of the

limitations of the base claim and any intervening claims.

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The following is a statement of reasons for the indication of allowable subject matter: The references of record do not teach or suggest a method for forming a capacitor comprising: after etching, the thickness of the third insulation layer over the second region is thinner than a thickness of the third insulation layer over the first region (claim 6); or etching the hard mask film using the photoresist pattern as a mask and etching the third and second insulation layers using the etched hard mask and the photoresist pattern.

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Conclusion

8. THIS ACTION IS MADE FINAL. Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the mailing date of this final action.

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9. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Kin-Chan Chen whose telephone number is (703) 305-

0222. If attempts to reach the examiner by telephone are unsuccessful, the examiner's

supervisor, Benjamin Utech can be reached on (703) 308-3836. The fax phone

numbers for the organization where this application or proceeding is assigned are (703)

872-9310 for regular communications and (703) 872-9311 for After Final

communications. Any inquiry of a general nature or relating to the status of this

application or proceeding should be directed to the receptionist whose telephone

number is (703) 308-2934.

Kin-Chan Chen Primary Examiner Art Unit 1765

K. C. HELen.

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K-C C June 17, 2003